Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/663,207	CHAN, ALBERT
Examiner	Art Unit
John L. Goff	1733

SEARCHED					
Class	Subclass	Date	Examiner		
156	276,307.7	10/25/2005	JLG		
252	519.31	10/25/2005	JLG		
252	519.33	10/25/2005	JLG		
252	520.1	10/25/2005	JLG		
Above	UPDATED	6/13/2006	JLG		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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